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- Ninth International Conference on Digital Information Management (ICDIM 2014)
- Fourth International Conference on Innovative Computing Technology (INTECH 2014)
- First International Conference on Future Generation Information and Communication Technology (FGICT 2014)
- Third International Conference on Future Generation Communication Technologies (FCGT 2014)

## Editorial

This issue has a few interesting papers as described below.

In the first paper on **“An Integrated Expert System for Mobile Phone Failure Diagnosis”**, the authors *Atallah AL-Shatnawi, Wafa Alsharafat, Bader Al-Fawaz* and *Rabah Alshobul* have designed an integrated knowledge base system for mobile phone failure diagnosis. Using CLIPS as expert system they have analysed different types of hardware failures. The testing and experiments have produced encouraging results.

In the next paper on **“A Novel Approach for Predicting the Length of Hospital Stay With Dbscan and Supervised Classification Algorithms”**, the authors *Panchami* and *Radhika* have proposed a patient management system where they used DBSCAN clustering to create the training set for classification of patients’ data. They have compared prediction models using accuracy, precision and recall and found that using DBSCAN as a precursor to classification gives better results.

*Azra Aryania, Ahmad Akbari, Mahdi Mohammadi, Bijan Raahemi* and *Elnaz Bigdeli* in the last paper on **“An Overlap-aware Positive Selection Algorithm using Variable-size Detectors”** proposed an enhanced positive selection algorithm to reduce the number of detectors required to cover the training sample space while resolving the issues of ambiguity of the test samples for which they applied clustering in the pre-processing phase. The authors have evaluated the performance of the proposed algorithm on five benchmark datasets. They found the experimental results confirm the superiority of the proposed method in terms of number of detectors and accuracy rate.

We hope that the research published in this issue mark significance.

## Editors